Progress in Surface Science

An International Review Journal

EDITOR-IN-CHIEF: Professor Sydney G. Davison

AUTHOR AND SUBJECT INDEX

Volume 41, 1992

PERGAMON PRESS

New York / Oxford / Seoul / Tokyo

Progress in Surface Science

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Production Editor: Douglas Cherno, Pergamon Press, Tarrytown, New York.

Publishing, Subscription and Advertising Offices: Pergamon Press Inc., 660 White Plains Road, Tarrytown, New York 10591-5153, U.S.A., INTERNET "PPI@PERGAMON.COM", and Pergamon Press Ltd., Headington Hill Hall, Oxford OX3 0BW, England.

Published Monthly: *Annual Institutional Subscription Rate* (1993): £360.00 (US$576.00). Sterling prices are definitive. US dollar prices are quoted for convenience only, and are subject to exchange rate fluctuation. Prices include postage and insurance and are subject to change without notice.

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PROGRESS IN QUANTUM ELECTRONICS

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Indexed/Abstracted in: *Curr Cont ASCA, Cam Sci Abstr, Chem Abstr Serv, Curr Cont Ind Sci Rev, Curr Cont Sci Cit Ind, Curr Cont SCISEARCH Data*

(00410)
Subscription Information
1993: Volume 17 (4 issues)
Annual subscription (1993) **£195.00** **US$312.00***
ISSN: 0079-6727

PERGAMON PRESS
Pergamon Press Ltd, Headington Hill Hall, Oxford OX3 0BW, UK
Pergamon Press Inc., 660 White Plains Road, Tarrytown, NY 10591-5153, USA
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(00220)
Subscription Information
1993: Volume 41 (12 issues)
Annual subscription (1993) **£770.00** **US$1232.00***
ISSN: 0022-5096

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